

Novel Kerf-Free PV Wafering that Provides a Low-Cost Approach to Generate Wafers from 150 mm to 50 mm

DOE Agreement #DE-EE0000594

PROJECT TITLE:

Novel Kerf-Free PV Wafering that Provides a Low-Cost Approach to Generate Wafers from 150 μm to 50 μm

PV Program

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Timeline

- Project start date: 8/1/2009
- Project end date: 7/31/2011
- Percent complete: 40%-50%

Budget

- Total project funding: \$7.78 M
 - DOE Share: \$3.0 M
 - SiGen Share: \$4.867 M
- DOE Funding received in FY09
 - \$1.5 M Plan (\$1.437 M Actual)
- Funding for FY10
 - \$ 1.5 M Plan

Barriers

- Barriers addressed
 - Materials Utilization & Cost
 - Manufacturing Processes
 - Efficiency

Partners

- REC Corp.
 - Factory automation
 - Bricking & grinding
 - Materials evaluation
- Project Lead
 - Silicon Genesis

- Conventional wire saw approach to wafering is limited by:
- Cost
 - Kerf-loss currently consumes > 50% of polysilicon
 - Silicon is turned into ‘sawdust’ mixed with abrasive slurry
 - Silicon recovery from slurry is costly, complex
 - Cost of slurry and associated production/recycle facility
 - Cost of ingot puller capacity to produce silicon lost to kerf
 - Cost of wafer washing and wet singulation
- Wafer thickness reduction
 - More efficient silicon usage driving need for thinner wafers
 - Sawing is a rough mechanical process
 - Obviously not well suited for micron scale layers of silicon
 - Industry encountering difficulty scaling down wire-sawn wafer thickness
 - Saw damage increases probability of wafer breakage
 - Tradeoff: thinner = slower cutting speed
 - Thickness variation, wafer to wafer variability → wafer binning




Source: Photon International

Relevance of Kerf-less Wafering to DOE Objectives

- Direct relevance to stated DOE SETP objectives
- ‘First-order’ impact on high-cost points in PV value chain: material usage and wafering
- Disruptive technology
- Potential for near-term commercialization
- Enabling technology for roadmap to very thin <100 micron wafers



 U.S. Department of Energy
Energy Efficiency and Renewable Energy
Bringing you a prosperous future where energy is clean, abundant, reliable, and affordable

The US has an opportunity to lead with new technologies in c-Si

The US has the history and technical expertise

- Leverage long solar heritage and leading R&D system

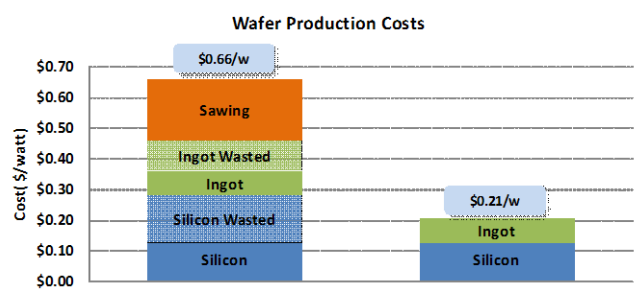
Different processes capture varying breadth of the PV value chain:

- Ingots → Wafers (Ion implant with liftoff)
- Poly Si Feedstock → Wafers (direct solidification)
- Silane → Cells (Epi growth with release)

The most promising technology is kerfless wafering

- Wafer >40% of panel cost
- Sawing (including wasted materials) accounts for over 65% of the wafer cost
- >50% of polysilicon lost to kerf

Wafer Production Costs



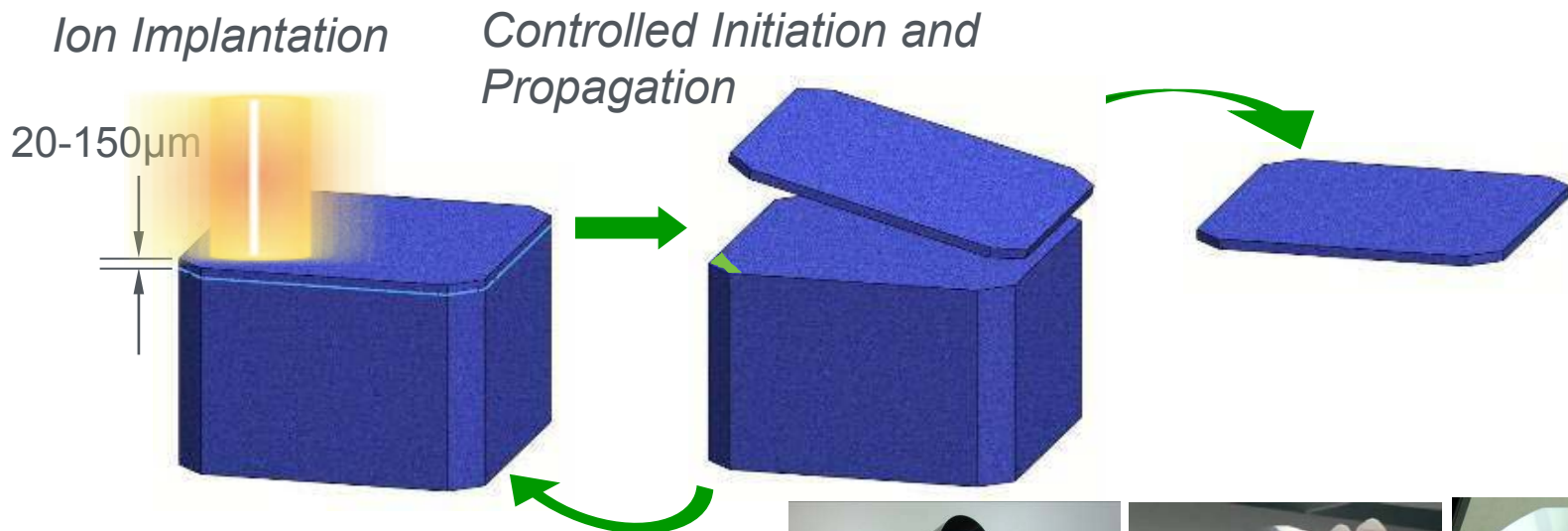
Process	Component	Cost (\$/watt)
2009 Standard Process	Silicon	\$0.10
	Silicon Wasted	\$0.10
	Ingot	\$0.10
	Ingot Wasted	\$0.10
	Sawing	\$0.26
Without Sawing Waste	Silicon	\$0.10
	Ingot	\$0.11

Source: Centrotherm, Photon International

U.S. Department of Energy Solar Energy Technologies Program Slide 6

Scott Stephens Presentation, DOE SETP

Silicon Genesis' Kerf-less Wafering (Approach)



- PolyMax is a two-step process
- Implant light ions into c-Si
 - Forms sub-surface cleave layer
- Controlled Cleave
 - Use a small high dose area to initiate a cleave
 - Propagate cleave through the lower dose area
 - Remove wafer
- Repeat on newly exposed brick surface



- SiGen has demonstrated kerf-less wafering on its R&D tools (previous work)
- Three thickness: 20, 50, 150 micron
- 125 mm and 156 mm square form factors
- High R&D yields
- No apparent problems due to progressive slicing
- <111> crystalline silicon

- Overall Goals
 - Lab-to-fab: Drive SiGen's PolyMax wafering technology toward widespread commercialization
 - Achieve substantial reductions in cost and waste and across value chain at existing wafer thicknesses
 - Enable the development and commercialization of <100 micron wafers to drive PV roadmaps
 - Develop two key pieces of production-grade process equipment: Implant and Cleave, plus automation components to tie them together
- Project Objectives
 1. Complete the design and test of an 'alpha' implant tool (1st year)
 2. Develop improved low-dose cleaving process/prototype (1st year)
 3. Develop an 'alpha' cleave tool (2nd year)
 4. Integrate implant and cleave tools together in semi-automated system. Optimize process. Begin pilot wafering (2nd year)
 5. Gather throughput and machine performance from 'alpha' tools to drive 'beta' and production tool design and factory design (1st & 2nd year)
 6. Gather pilot cost and yield data to validate cost modeling (2nd year)

- Implant: Most expensive process step
 - Minimize \$/mA:
 - Scale up R&D tool currents >100x with *high current accelerator*.
 - *Implant many bricks in parallel*
 - Minimize dose required for cleave:
 - *Use patterned implant*: Concentrate high dose only in small area to initiate crack. Use lower average dose to propagate crack across brick.
 - *Use surface heating/temp control by ion beam for process optimization*
 - Develop high-speed ion beam scanner for maximum process flexibility: dose and thermal control
 - Develop efficient, low thermal resistance in-vacuum brick cooling technique

- Implanter design and parts fabrication & procurement is 100% complete.
 - All parts received at SiGen.
- Facility is 100% complete
 - Concrete radiation vault construction complete. Radiation safety system tested.
 - High initial gamma ray flux from accelerator mitigated with additional shielding
 - Coolant systems, gas delivery, electrical power in place and functional
- Ion Implant *System* Status
 - 4 phase integration *underway now*
 1. Get accelerator running stably at modest beam currents. (Completed)
 2. We are here → Couple accelerator to beamline; transport and scan beam
 3. Couple beamline to endstation; achieve first beam-on-silicon
 4. Scale-up beam current to spec current and energy
 - Expect first beam-on-silicon in 6 weeks. Will hit milestone for first implants by Aug 2010.
- Next steps
 - Equipment tuning and testing
 - Process development and optimization. High power implant capability will open new process capability/space for dose reduction. Increases availability of material for cleaving tests.
 - Wafer sampling to customers

- Endstation – In-line, vacuum loadlocked process chamber. Handles and cools bricks during implant
 - Brick cooling: Tested on bench (in vacuum) Demonstrated to have acceptable heat transfer coefficients 61% of (somewhat arbitrary) design target.
 - Mechanical reliability: Several hundred trays of bricks ‘dry processed’ (no beam). No reliability issues.
 - Mechanical throughput: Measured on actual endstation. Exceeds targets. Beam current limited, NOT mechanical/pump limited
- Accelerator – Generates ion beam and accelerates it to high energy
 - Alpha beam energy spec: 2-4 MeV (50-150 micron wafers)
 - Max energy achieved to date 3.5 MeV
 - Beam current scale up:
 - Alpha specification: ~ 50% of Production tool spec
 - Achieved to date: ~10% of Production tool spec
 - Scale-up goal: 2x Production spec within 2 years
- Beamline – Transports beam to Endstation
 - All parts assembled, leak tight
 - Bench tests of scanner system passed 100%. Scanner speed meets spec.
 - Beam transport, debugging, testing and firming up software controls are underway
- Key Equipment Testing Planned
 - Brick cooling & temperature
 - Tray temperature
 - Longevity of consumables (parts struck by beam)
 - Measurements of radiation (activation) of silicon and machine parts
 - Any reliability issues due to thermal expansion

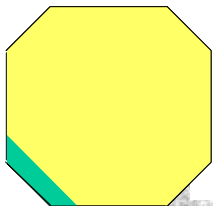


Endstation

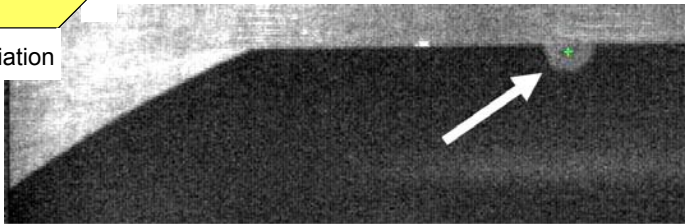


Process Tray

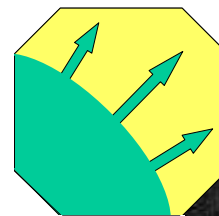
- Cleave: Improve and optimize for lower doses. Reduce thermal budget
 - Conventional approaches require ion doses which are high, limiting productivity
 - To achieve cost and productivity targets, reduce ion dose needed for cleaving
 - SiGen's strategy is to apply a source of external stress or energy to *drive* the crack
 - Implanted layer serves to *guide* the crack at lower doses
 - Develop benchtop prototypes to evaluate several different novel approaches to applying external energy and select
 - Existing iso-thermal cleaving approach is currently used



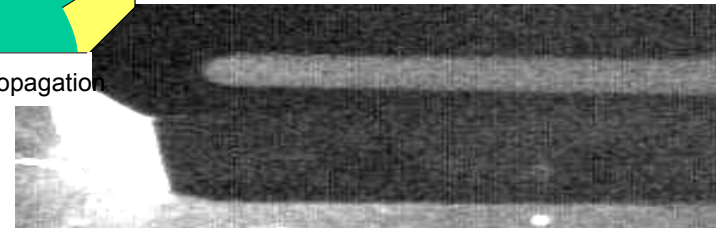
1. Initiation



IR Image of a post-initiated area (pre-existing work)

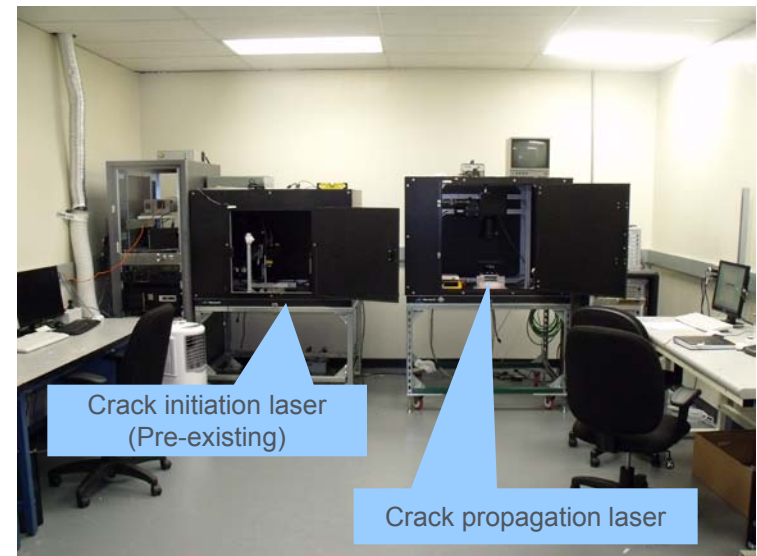


2. Propagation

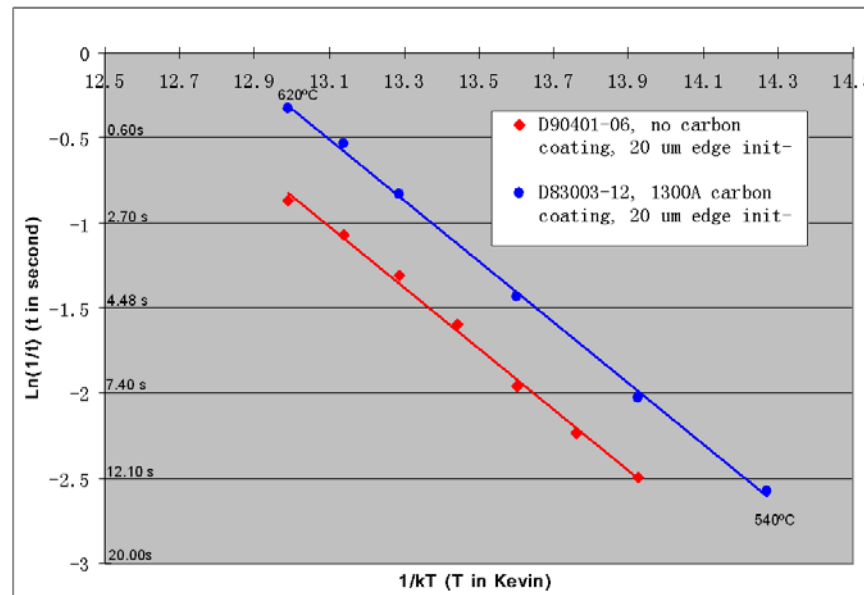


IR Image of a propagation path (pre-existing work)

- Developed scanned laser cleaving test-beds for crack initiation (pre-existing) and propagation
- Developed repeatable laser crack-initiation recipes for 20 micron and 50 micron thick wafers
- Demonstrated first laser initiation of 150 micron thick wafer
- Controlled-depth cleaves have been successfully propagated starting from these initiation points, to form silicon films of moderate (centimeter-scale) size.



- Confirmed laser crack propagation theory in numerous experiments using two low thermal budget propagation techniques.
- Laser Initiation described by first-order kinetics, characterized by an activation energy
- Scanned-beam pyrometry system calibrated using known-emissivity surface. Temperature accuracy on bare silicon improved.
- Increased area of beam-cleaved film



- Implant
 - Assess hardware results from initial alpha implanter operation (2010/2011)
 - Assess life of components struck by beam and develop improvement plan (2010)
 - Kickoff of beta tool design (2010)
 - Continue scale-up of beam current to spec and beyond if possible (2010, 2011)
 - Make improvements in equipment reliability, uptime etc (2010, 2011)
 - Kickoff factory automation design (2010)
- Cleave:
 - Complete cleave prototype evaluation tools (2010)
 - Select and develop alpha cleave tool (2011)
 - Ongoing process optimization and dose reduction (2010, 2011)

- REC Corporation (Norway)
 - Customer/Industrial Partner. Not in DOE Solar Program.
 - SiGen & REC collaboration is extensive:
 - Commercial relationship with tool supply agreement
 - Wafer samples supplied by SiGen, evaluated by REC
 - Development of cell process technologies for thin wafers, <111> texturization by REC
 - Inputs by REC into design of equipment
 - Factory layout and automation
 - Testing and evaluation of alpha machines at SiGen
 - Planned Beta site at REC
- Company A (name withheld due to confidentiality)
 - Potential Customer, Not in DOE Solar Program.
 - Company A has received and evaluated SiGen wafer samples
 - Material quality, lifetime evaluated
 - Cells fabricated, efficiency comparable to CZ reference wafer
- NorSun Corp (Norway)
 - Customer/Industrial Partner.
 - Commercial agreements
 - Not in DOE Solar Program.

- Integration of alpha Implanter tool is progressing well and on track to achieve first implants by Aug. 2010. No show-stoppers.
- Availability of high-power alpha Implanter will
 - Open new areas of process space for dose reduction
 - Dramatically increase rate at which SiGen can perform process optimization experiments
 - Increase supply of early samples to partners/customers
 - Provide a lot of practical ‘learnings’ about the equipment that will be used for the beta
- Cleave theory is now well-developed
- Several new cleave modes and possible techniques were developed
- Prototype test-fixtures covering these techniques are being fabricated now